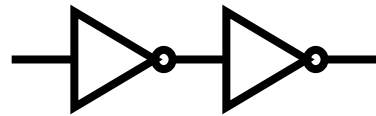
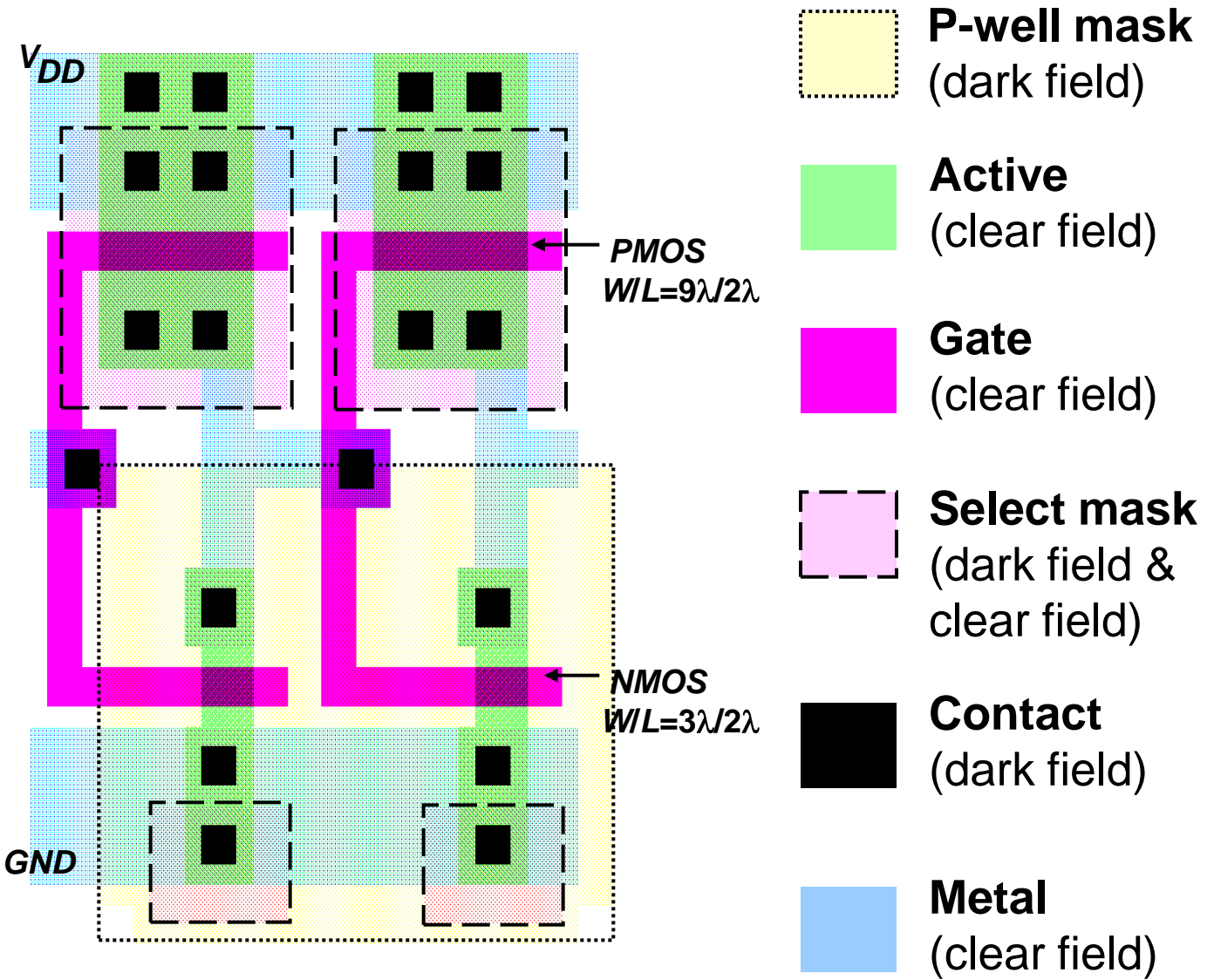


CMOS Inverter Layout



Note body contacts:

- p-well to GND
- n-substrate to V_{DD}



Visualizing Layouts and Cross-Sections with SIMPLer

SIMPL is a CAD tool created by Prof. Neureuther's group

- allows IC designers to visualize device cross-sections corresponding to a fabrication process and physical layout.

A Berkeley undergraduate student, Harlan Hile, created a mini-version of SIMPL (called SIMPLer) for EE40.

- It's a JAVA program -> can be run on any computer, as well as on a web server.

- A 3D version SIMPL-GL can be accessed at

http://cuervo2.eecs.berkeley.edu/Volcano/simpl_gl/main.htm

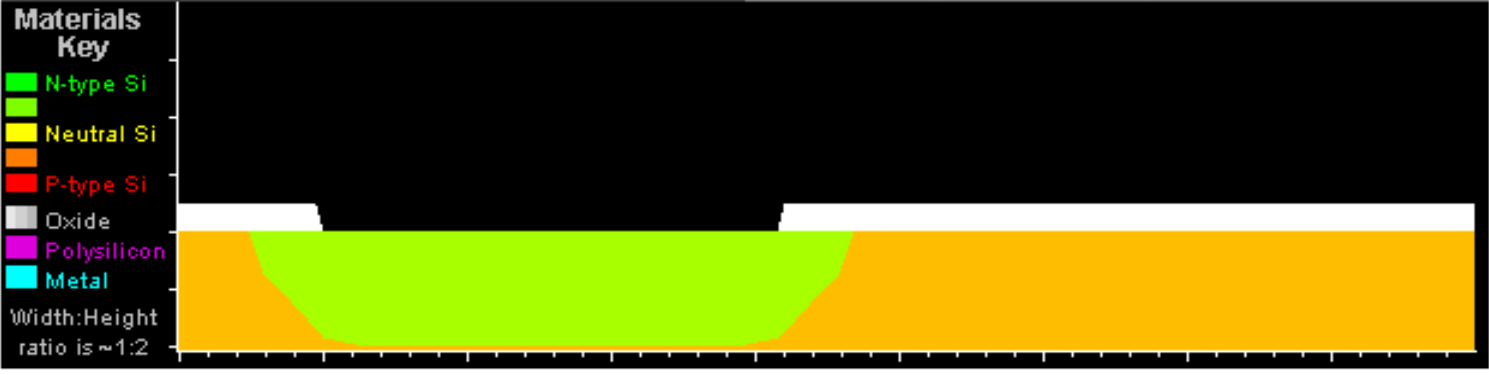
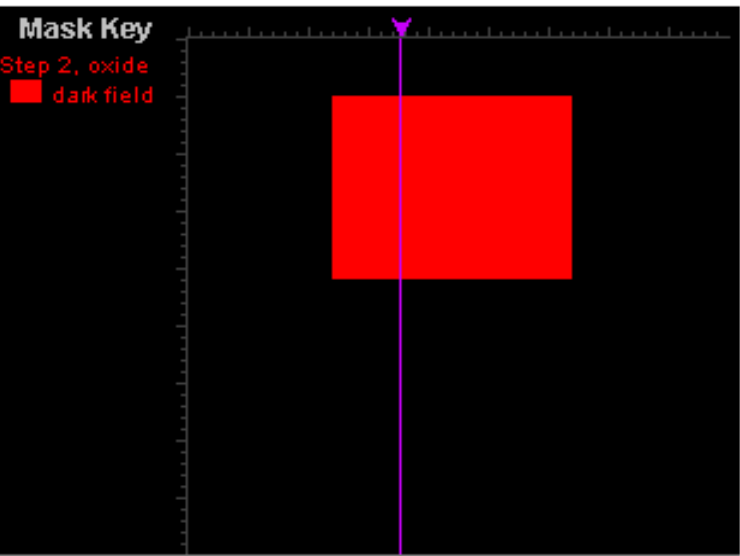
Step Number 3

implant donors

with a concentration of ions per cm²
and anneal to a depth of nanometers.

Delete Step Add Step

Restart Calculate Cross-Section





Bookmarks Netsite: <http://www.ocf.berkeley.edu/~hhile/SIMPLer/SIMPLer.htm>

What's Related

IRIS, Instructi

Step Number 12

implant acceptors

with a concentration of ions per cm²

and anneal to a depth of nanometers.

Delete Step

Add Step

Restart

Calculate Cross-Section

Mask Key

Step 2, oxide

■ dark field

Step 4, oxide

■ clear field

Step 6, oxide

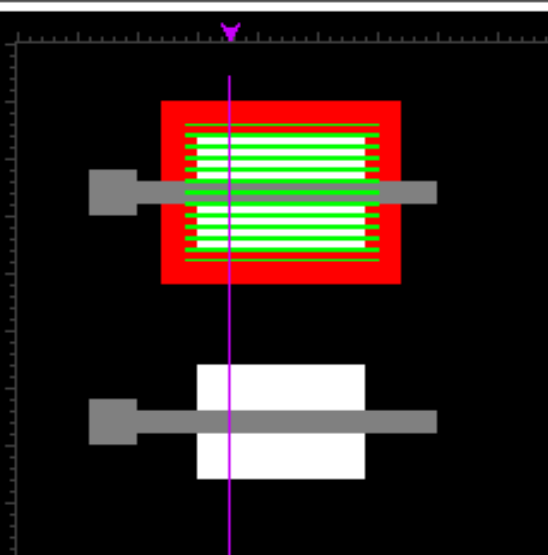
■ dark field

Step 9, poly

■ clear field

Step 11, photo

≡ dark field



Materials Key

■ N-type Si

■ Neutral Si

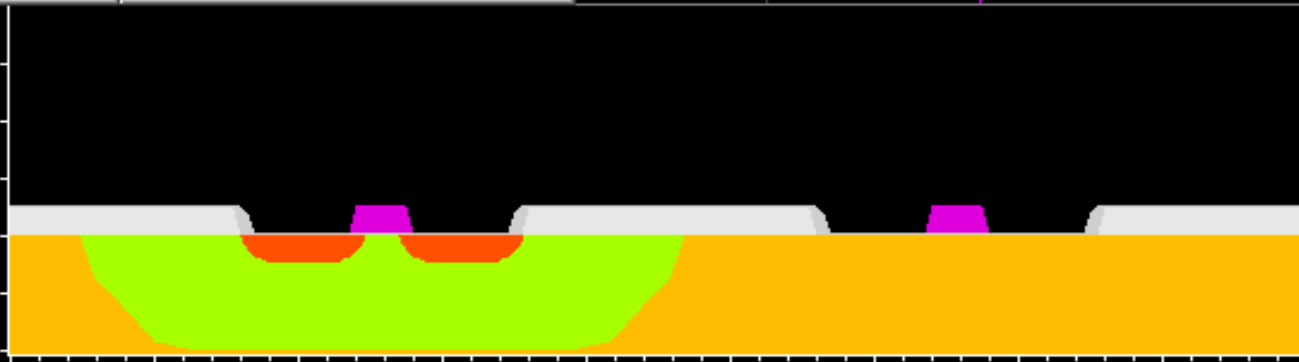
■ P-type Si

■ Oxide

■ Polysilicon

■ Metal

Width:Height
ratio is ~1:2





Step Number 15

 with a concentration of ions per cm²

 and anneal to a depth of nanometers.

Delete Step

Add Step

Restart

Calculate Cross-Section

Mask Key

Step 2, oxide

■ dark field

Step 4, oxide

■ clear field

Step 6, oxide

■ dark field

Step 9, poly

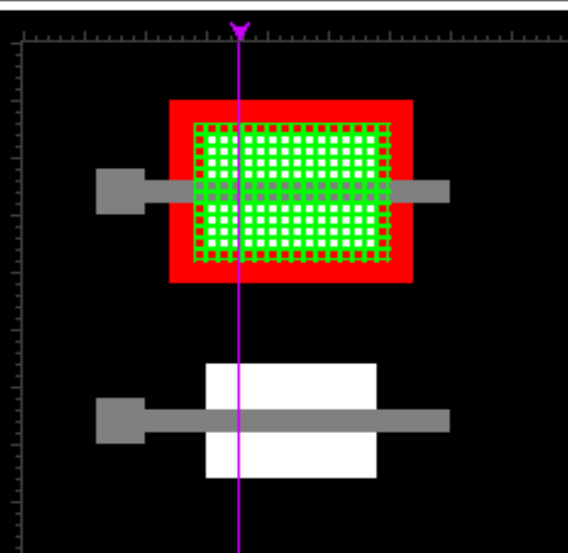
■ clear field

Step 11, photo

▬ dark field

Step 14, photo

▬ clear field



Materials Key

■ N-type Si

■ Neutral Si

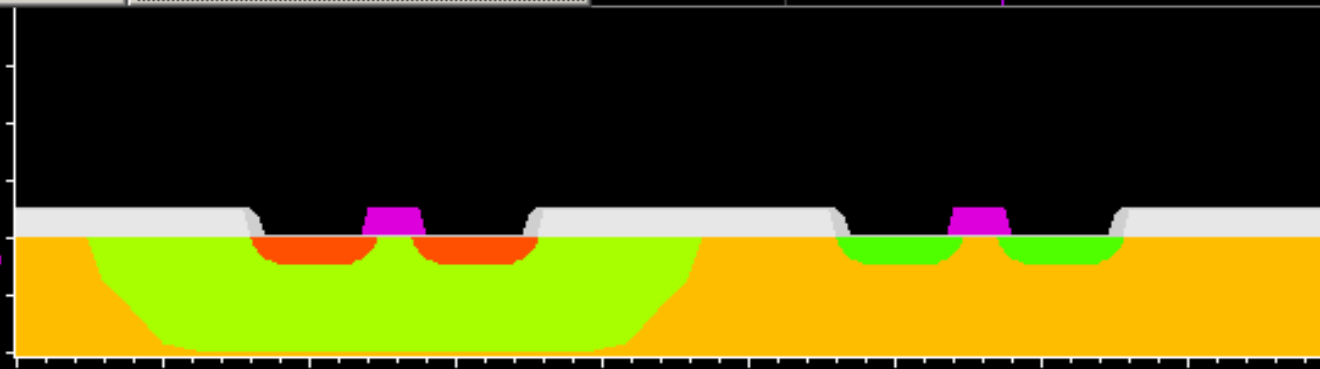
■ P-type Si

■ Oxide

■ Polysilicon

■ Metal

Width:Height ratio is ~1:2



Print this page



Step Number 17

pattern oxide

 with a **dark** field mask. Use the color

magenta and the pattern **solid**

to display this mask. The current draw mode is:

 draw erase

Delete Step

Add Step

Restart

Calculate Cross-Section

Mask Key

Step 2, oxide

dark field

Step 4, oxide

clear field

Step 6, oxide

dark field

Step 9, poly

clear field

Step 11, photo

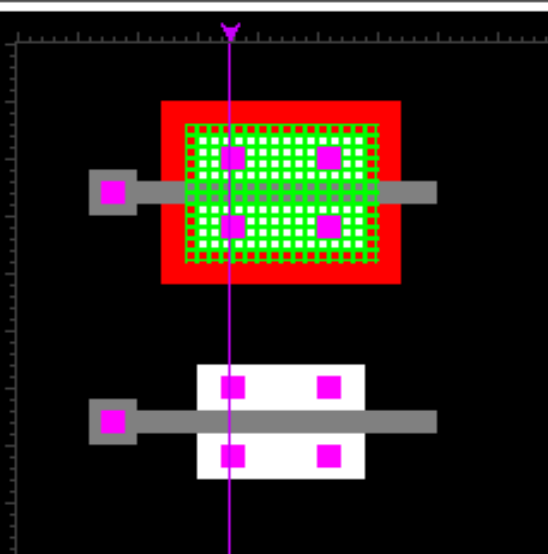
dark field

Step 14, photo

clear field

Step 17, oxide

dark field



Materials Key

N-type Si

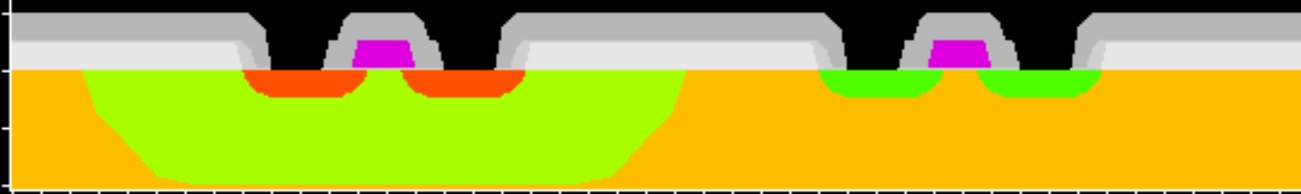
Neutral Si

P-type Si

Oxide

Polysilicon

Metal

 Width:Height
ratio is ~1:2


Step Number 19

pattern metal

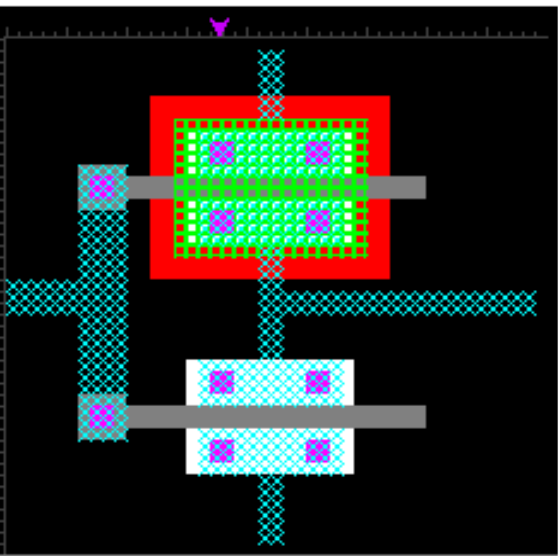
with a **clear** field mask. Use the color **cyan** and the pattern **X's** to display this mask. The current draw mode is:

draw erase

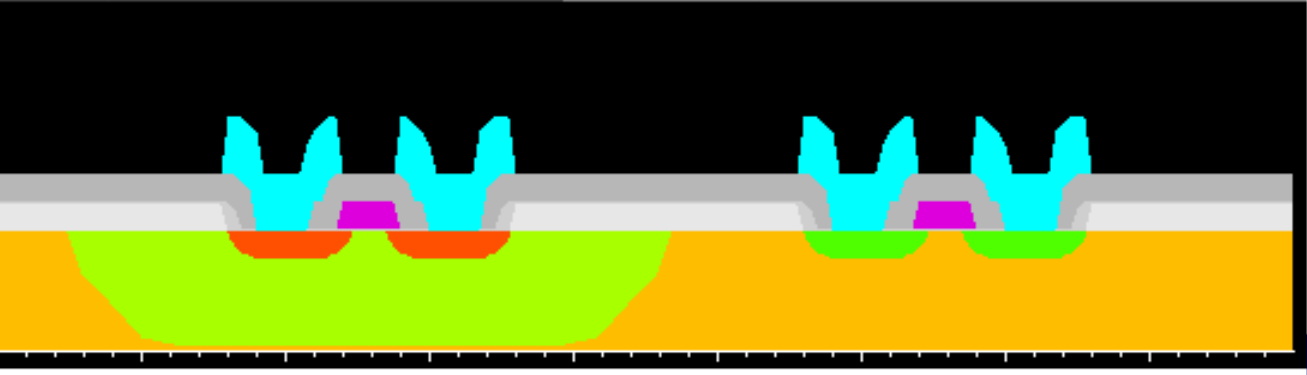
Delete Step Add Step

Restart Calculate Cross-Section

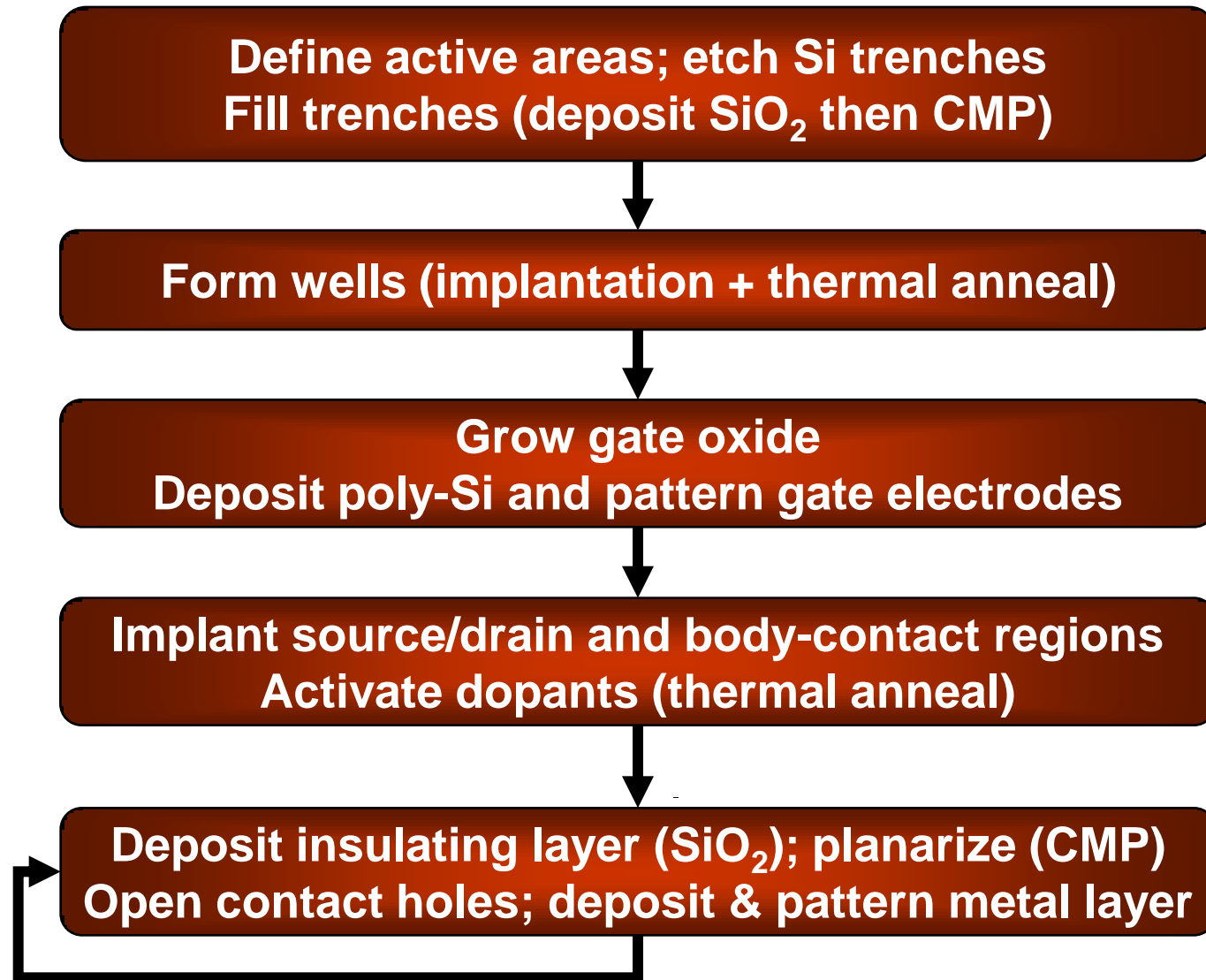
- #### Mask Key
- Step 2, oxide ■ dark field
 - Step 4, oxide ■ clear field
 - Step 6, oxide ■ dark field
 - Step 9, poly ■ clear field
 - Step 11, photo dark field
 - Step 14, photo clear field
 - Step 17, oxide ■ dark field
 - Step 19, metal clear field



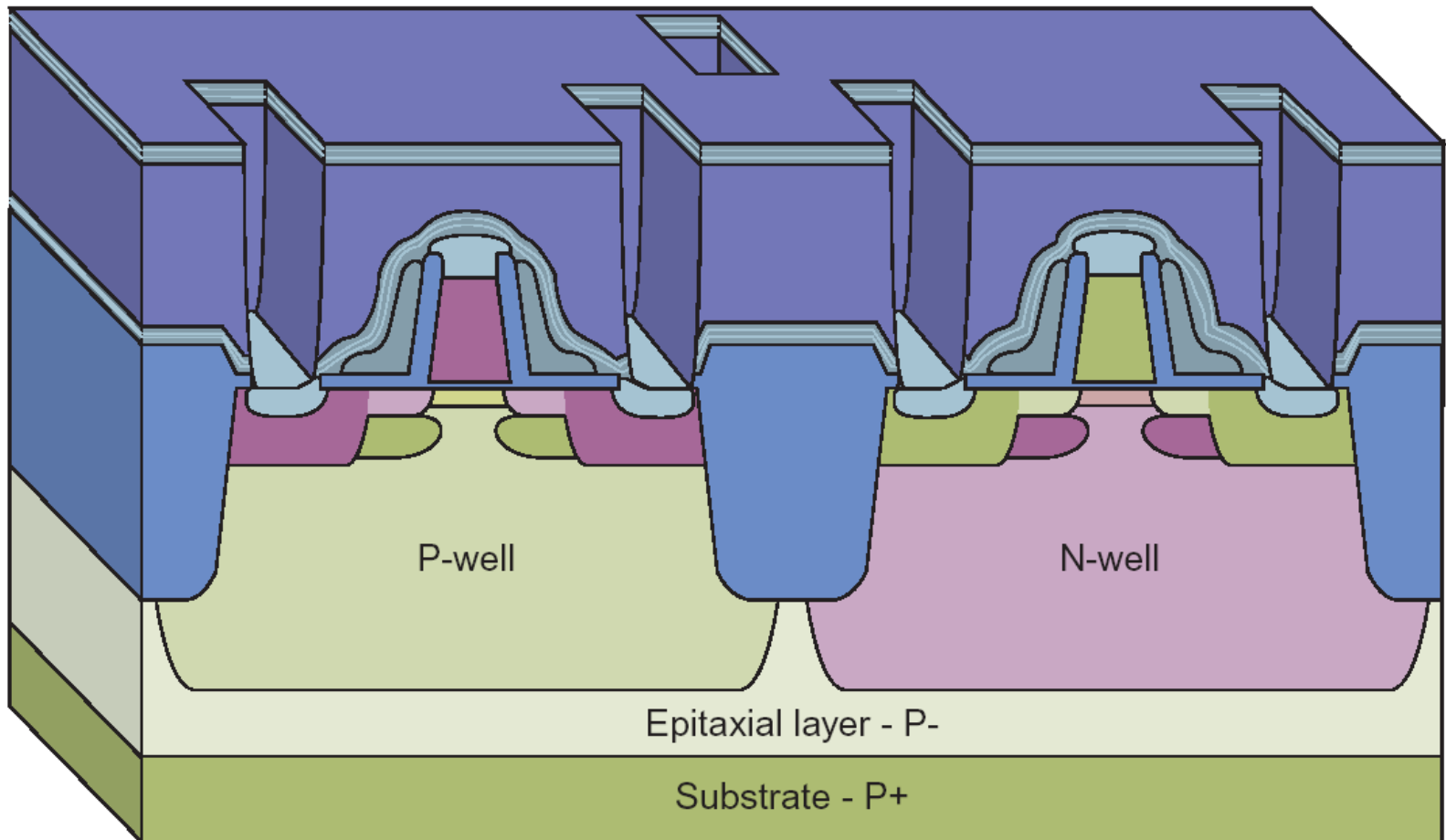
- #### Materials Key
- N-type Si
 - Neutral Si
 - P-type Si
 - Oxide
 - Polysilicon
 - Metal
- Width:Height ratio is ~1:2



Twin Well + STI CMOS Process

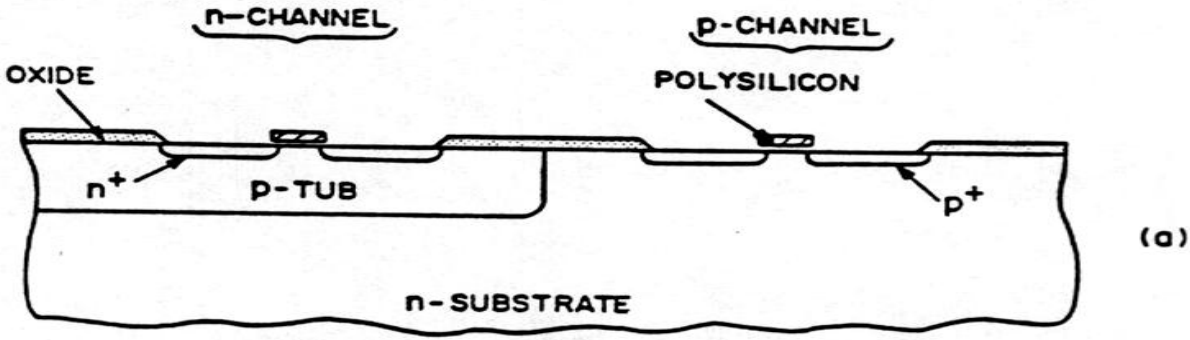


3D view of a CMOS inverter after contact etch.



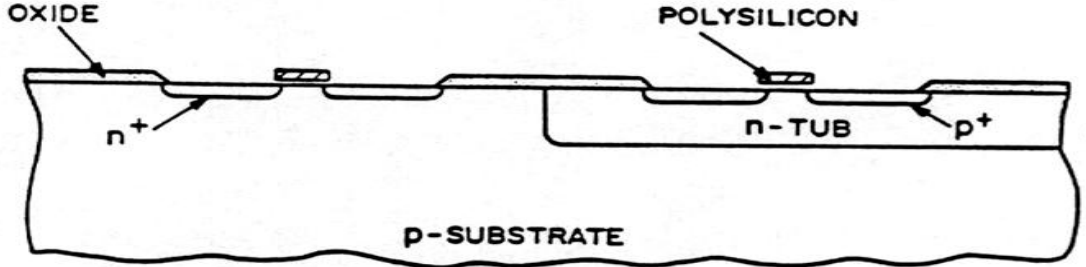
Well Engineering

P-tub



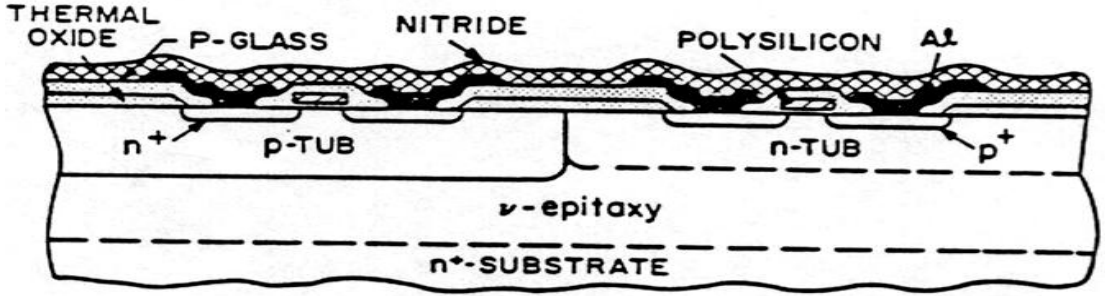
(a)

N-tub



(b)

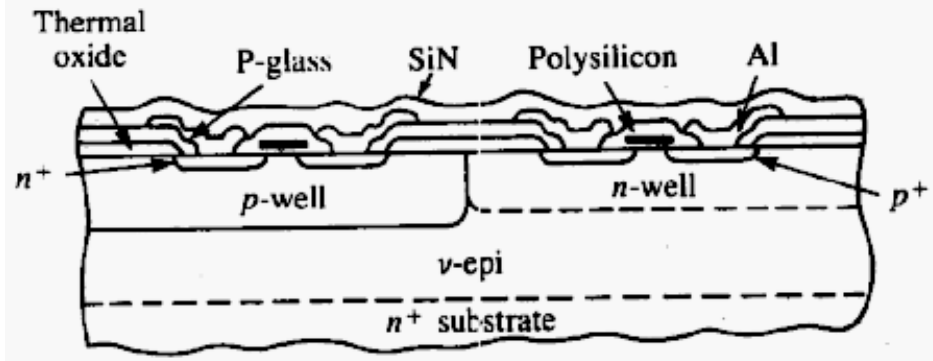
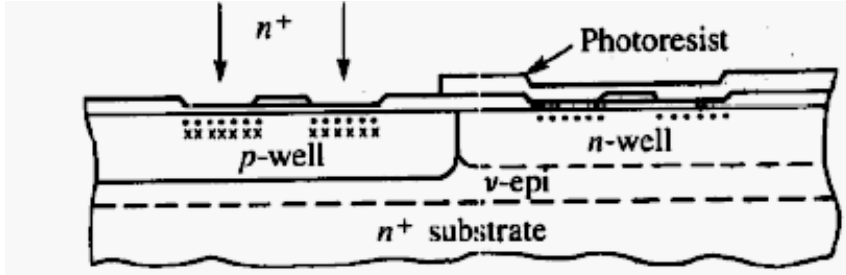
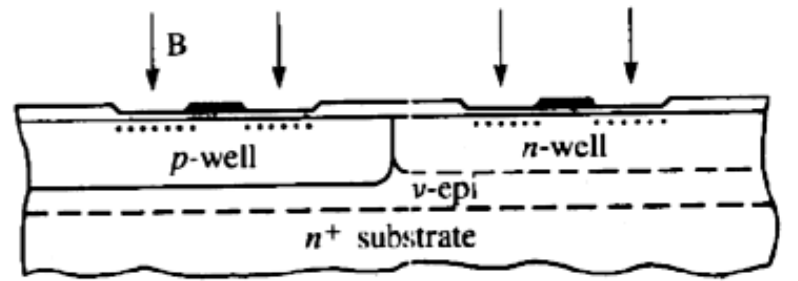
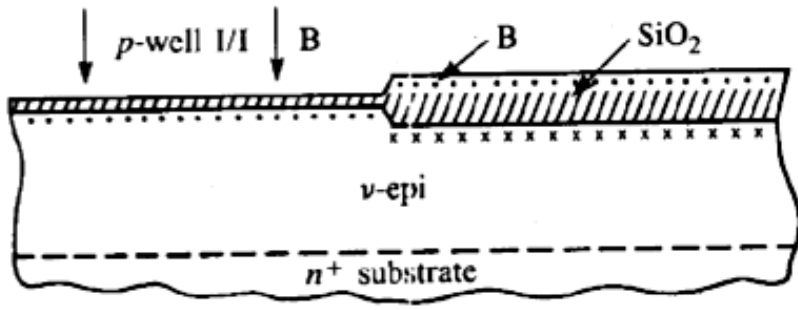
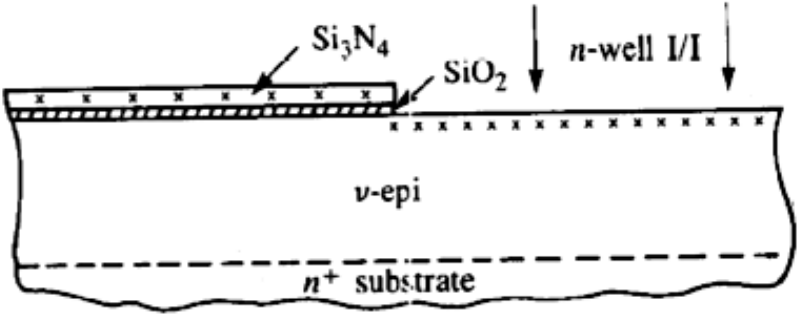
Twin Tub



(c)

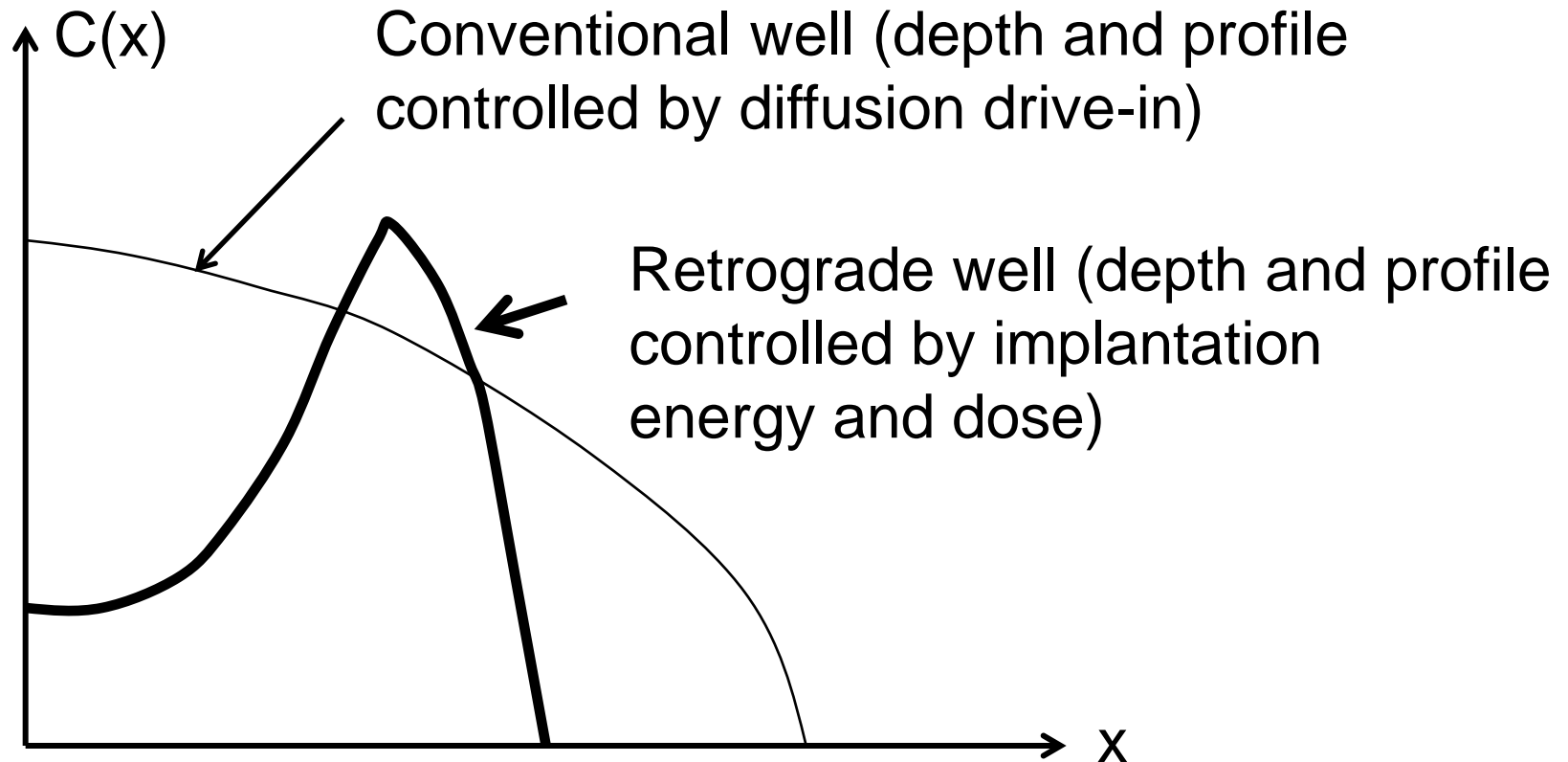
Various CMOS structures. (a) p tub. (b) n tub. (c) twin tub.

Twin Well CMOS Process Flow

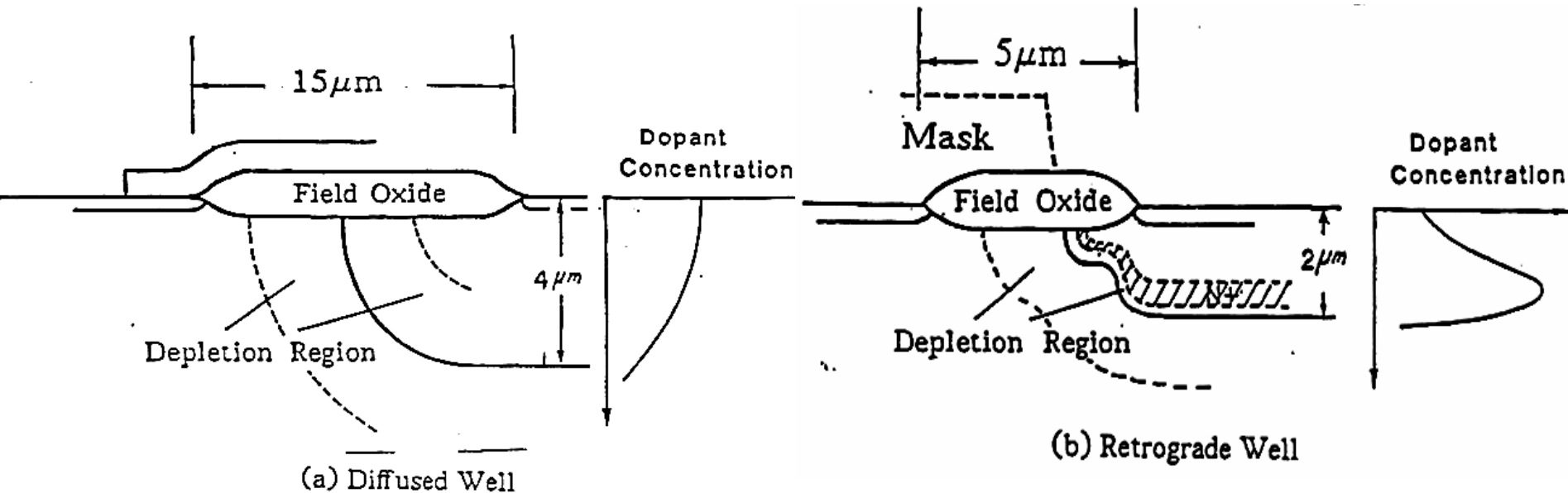


Retrograde Well

- formed by high energy ($>200\text{keV}$) implantation

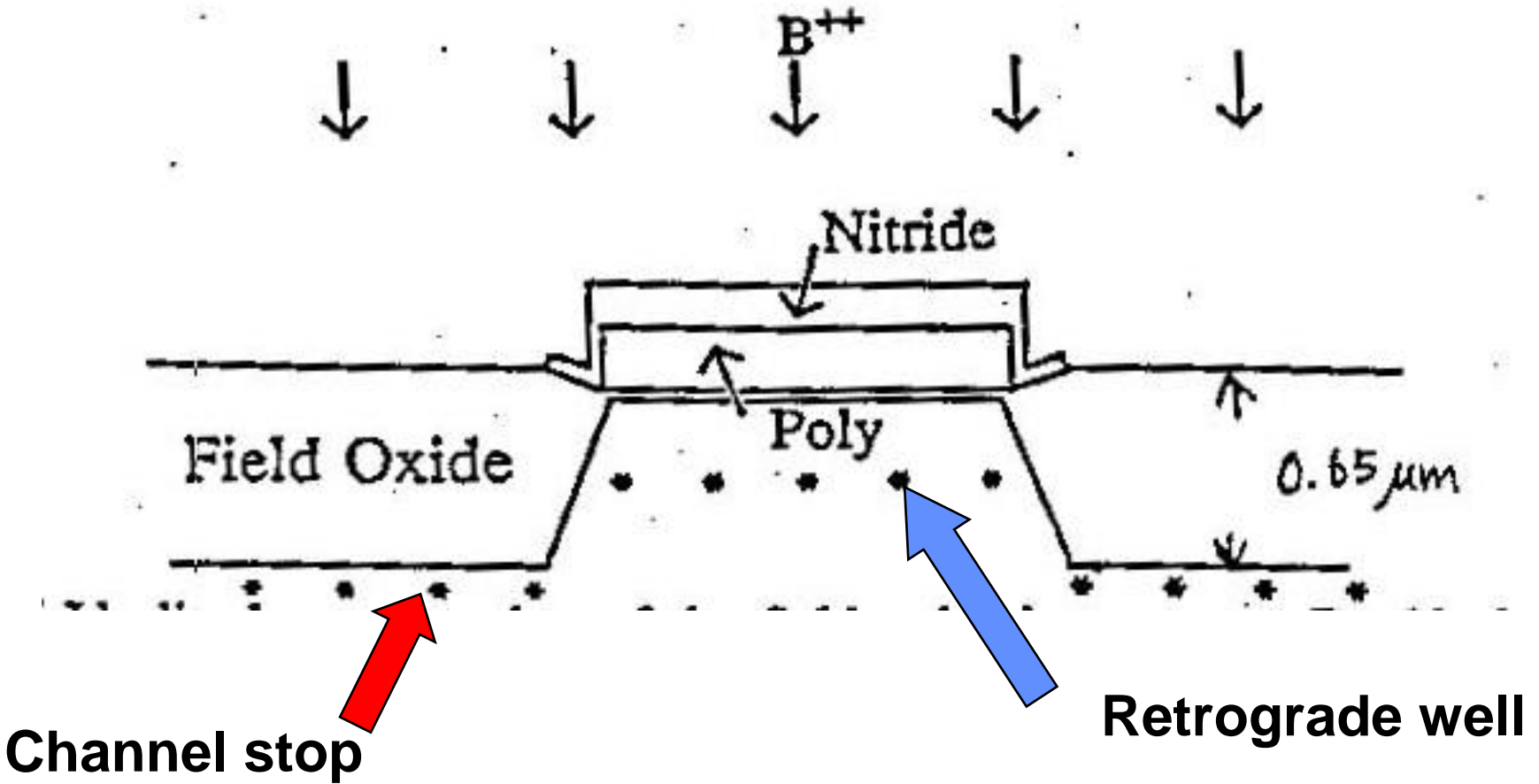


Conventional vs Retrograde Well



- 1) Very low thermal budget for well formation
(no need for diffusion drive-in)
- 2) Retrograde Well is formed **AFTER** field oxidation
⇒ small lateral diffusion and localized high conc under FOX

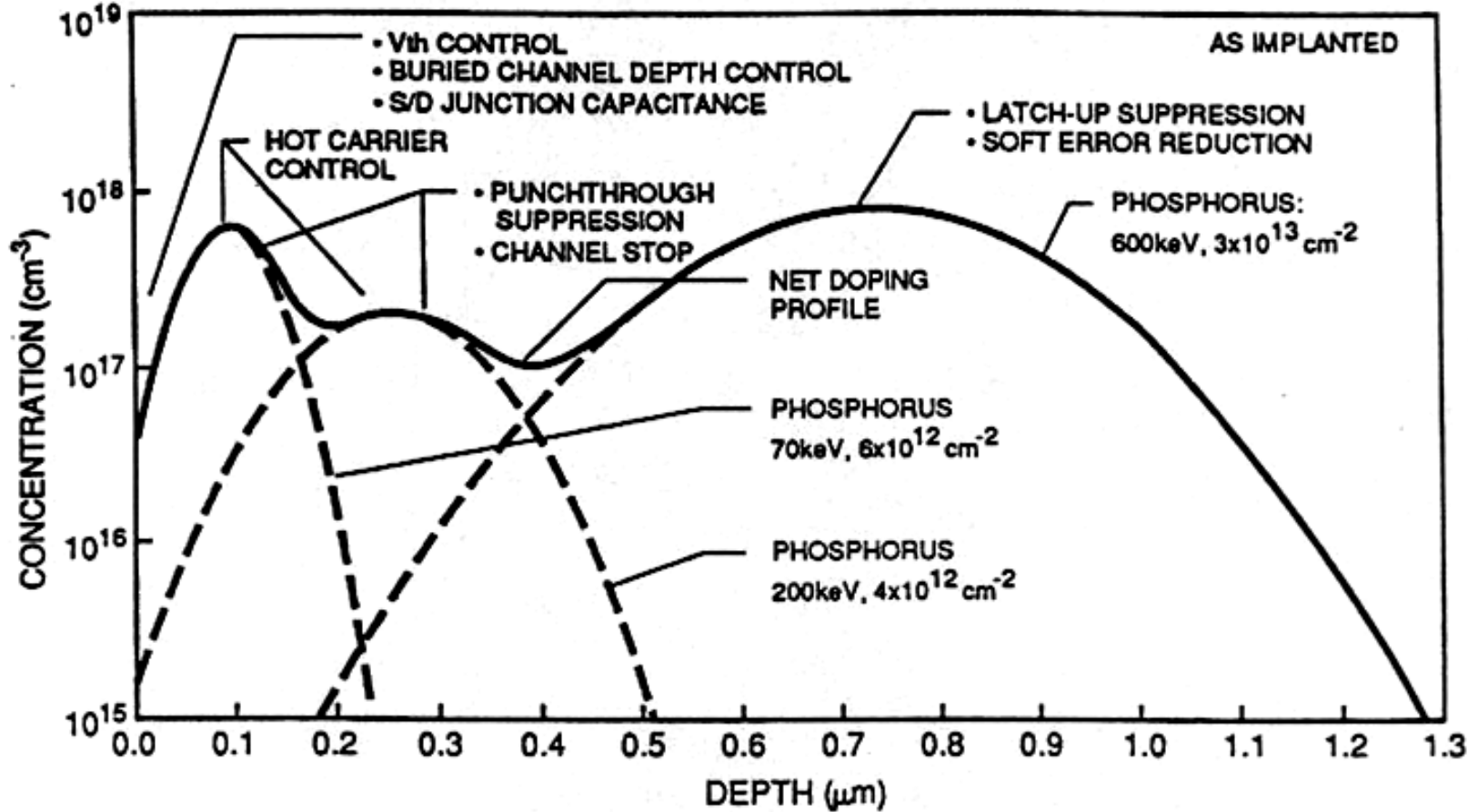
Example: Formation of Channel Stop and Retrograde Well in a single step



Multiple Implants for Well Engineering

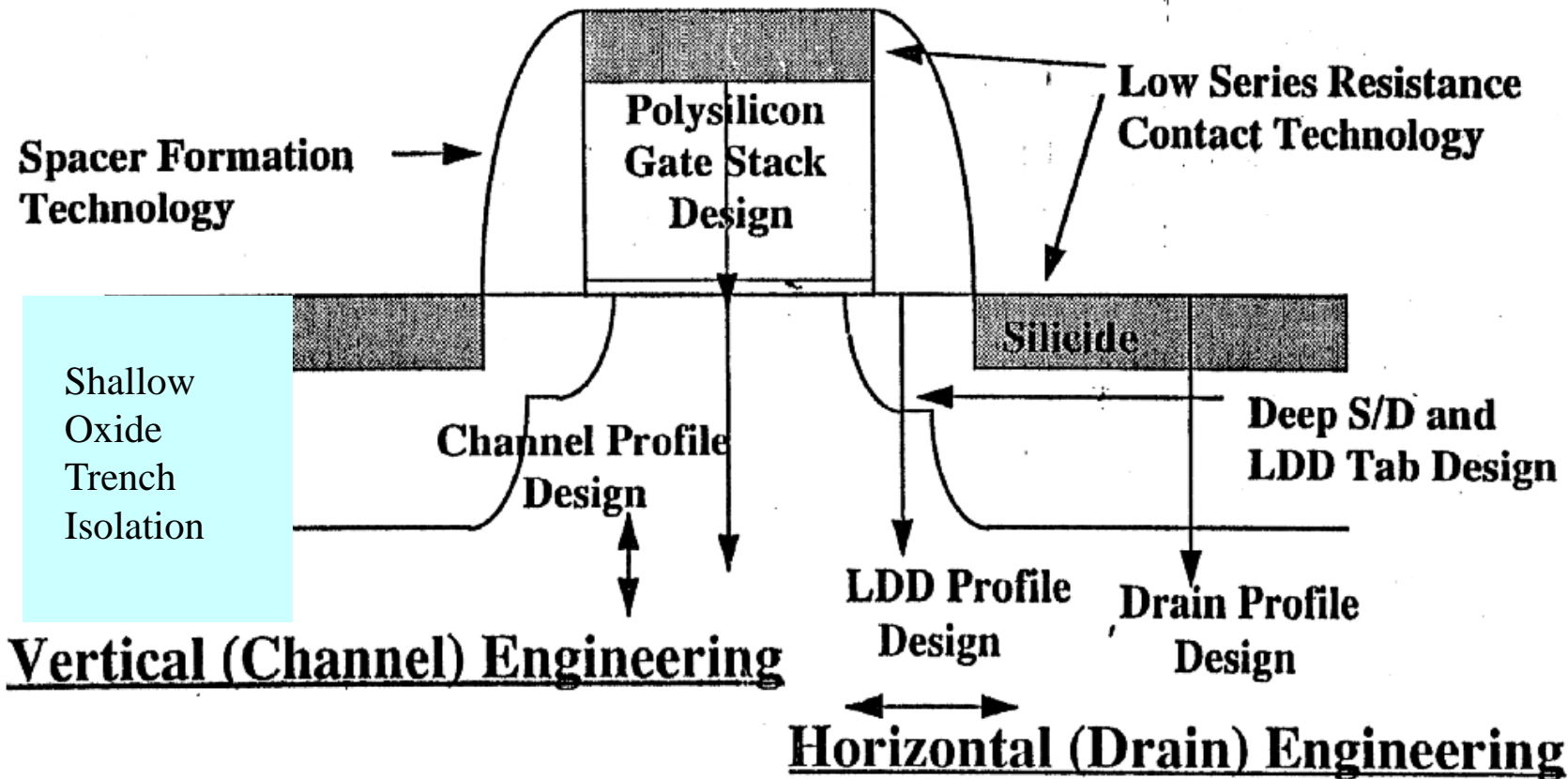
Advanced "Profiled" Wells for Sub-Micron Devices (after Reference 136)

A. N-Well Vertical Profile* (under the gate)

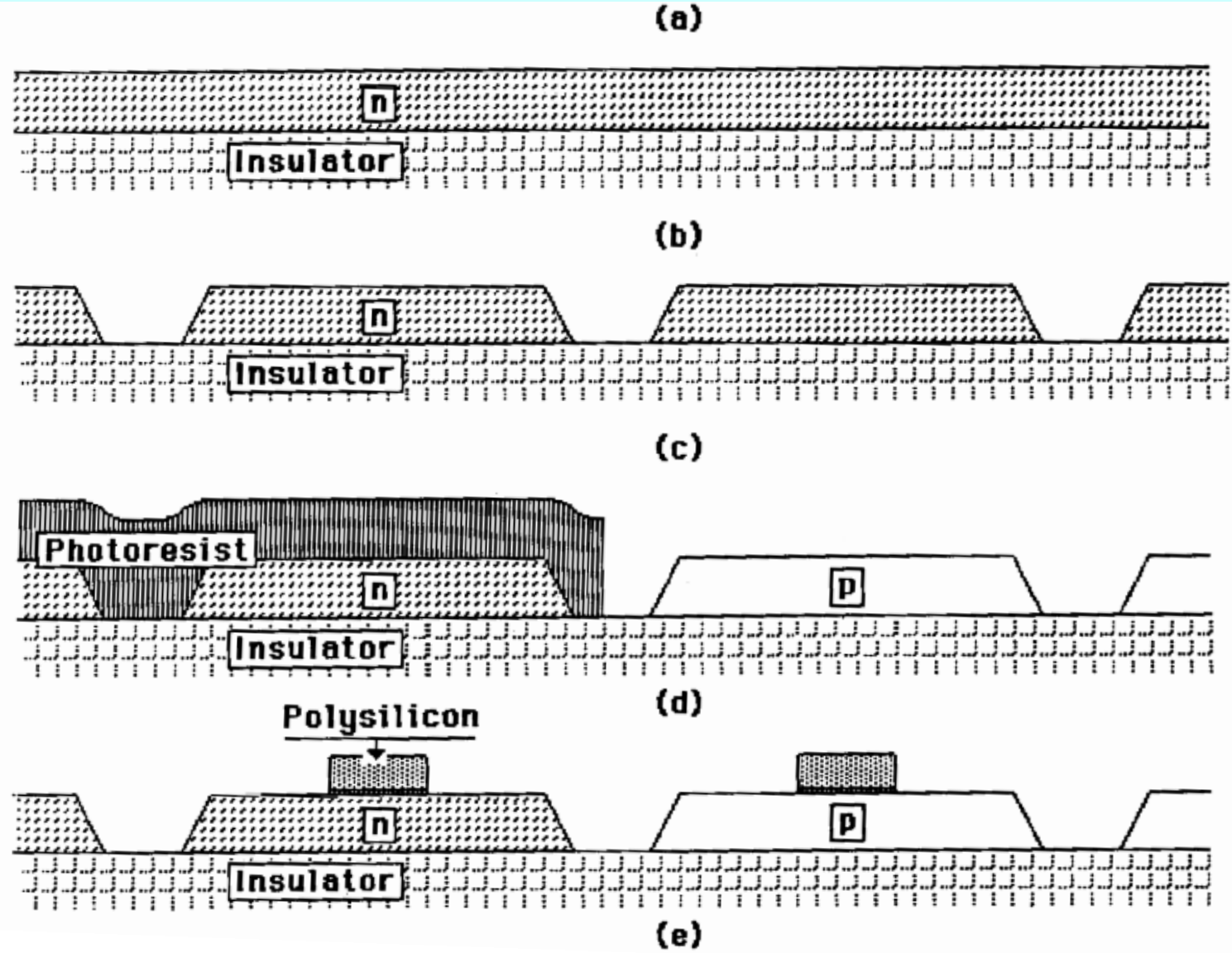


Channel Engineering

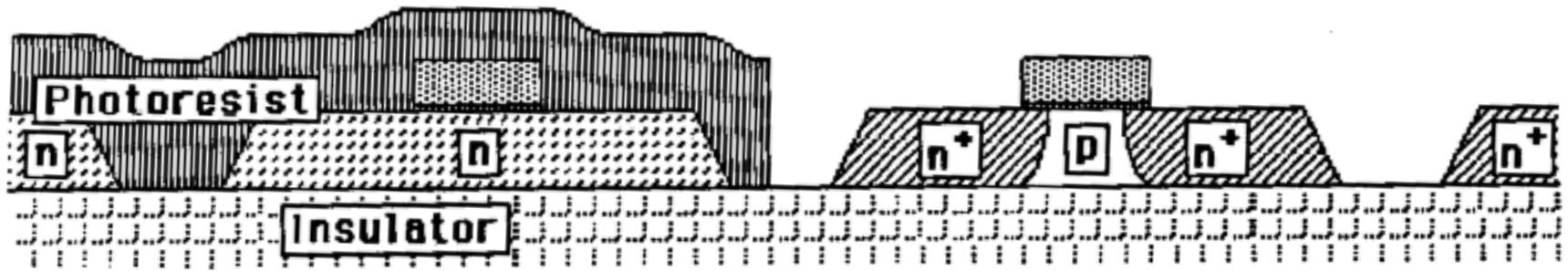
SUBMICRON DEVICE STRUCTURE AND DESIGN



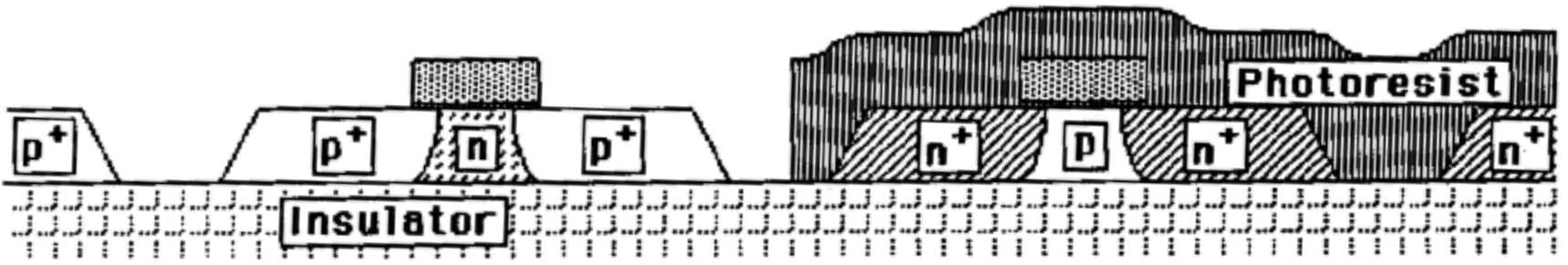
Generic Silicon-on-Insulator (SOI) CMOS Process Flow



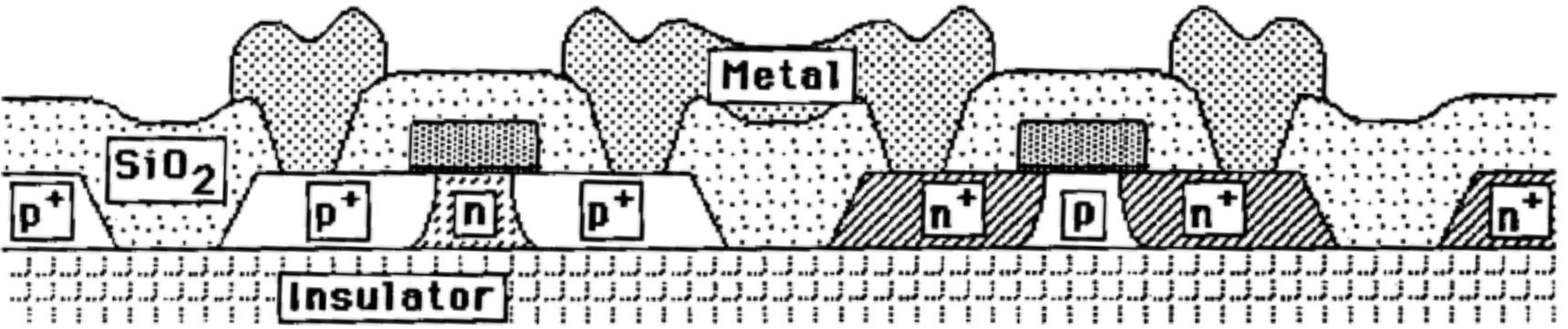
SOI Process Flow (continued)



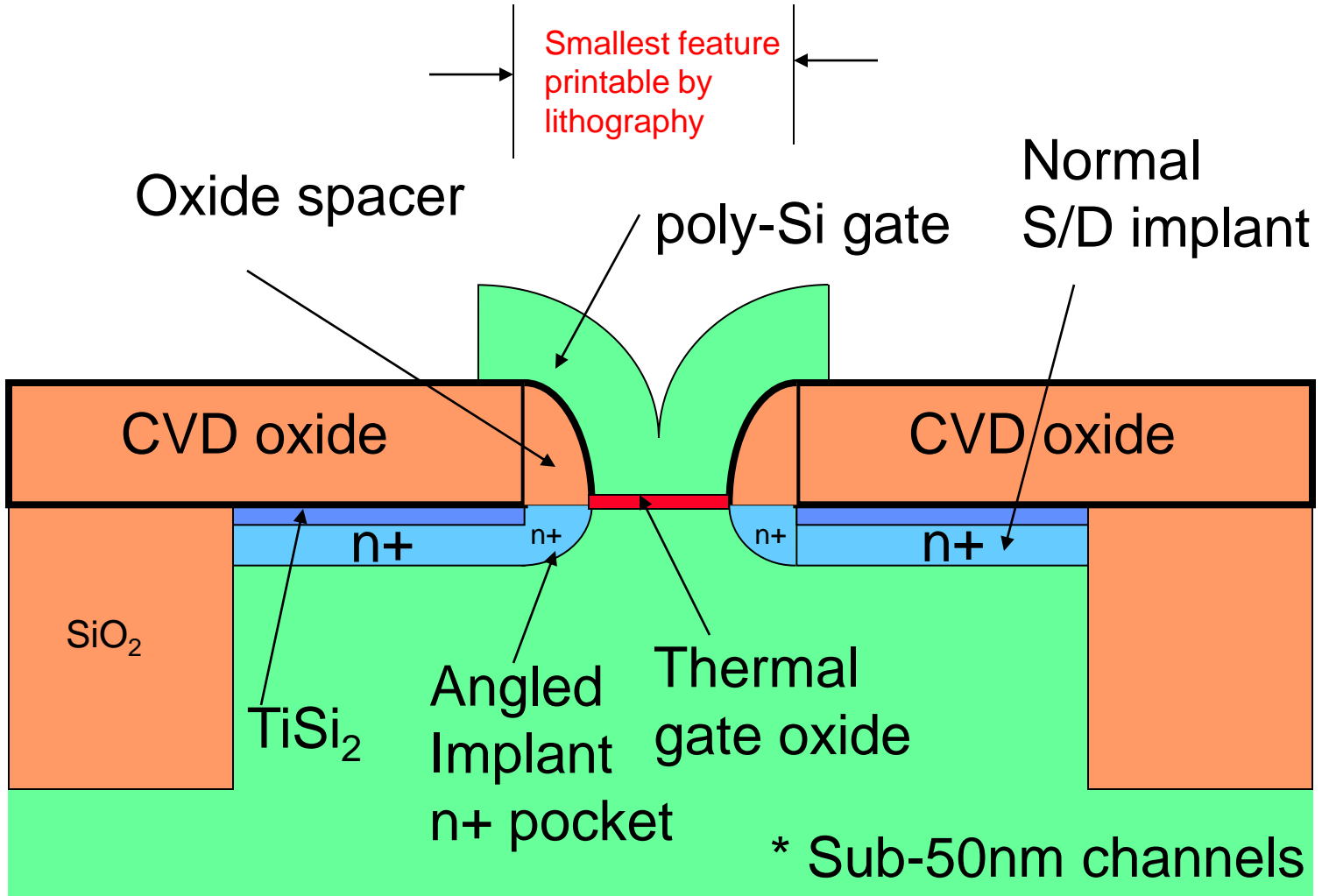
(f)



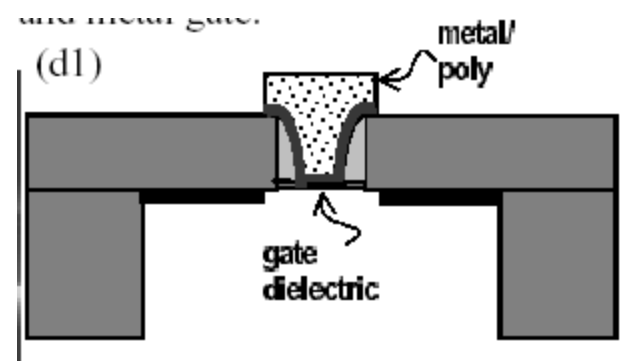
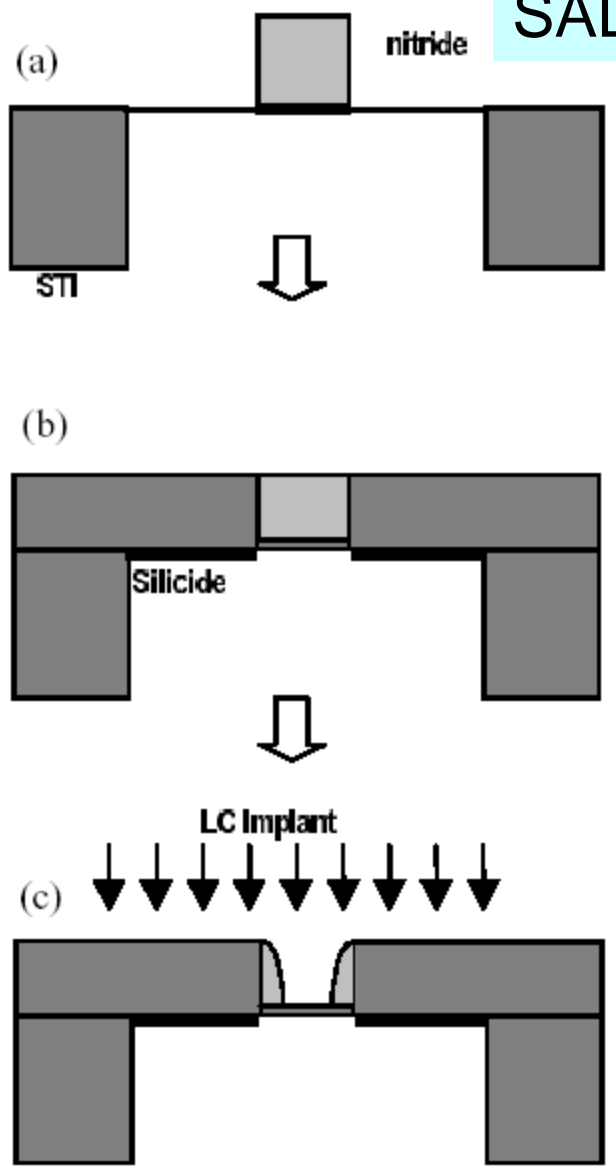
(g)



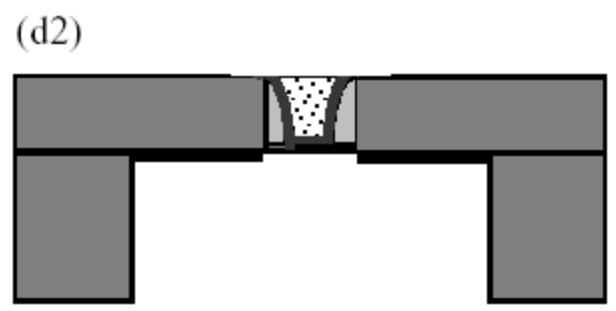
Self-Aligned Channel V-gate by Optical Lithography (SALVO) Process



SALVO Process Flow



or



See Homework Problem

Chang et al, IEDM 2000

SUMMARY OF IC PROCESS INTEGRATION MODULE

- Self aligned techniques: channel stop, Source/Drain, LDD, SALICIDE
- How to read process flow descriptions and cross-sections
- Generic NMOS Process with LOCOS
- Generic CMOS Process with LOCOS and single well
- Modified Processes:
- Shallow Trench Isolation (STI), Twin Wells, Retrograde Well, SOI CMOS